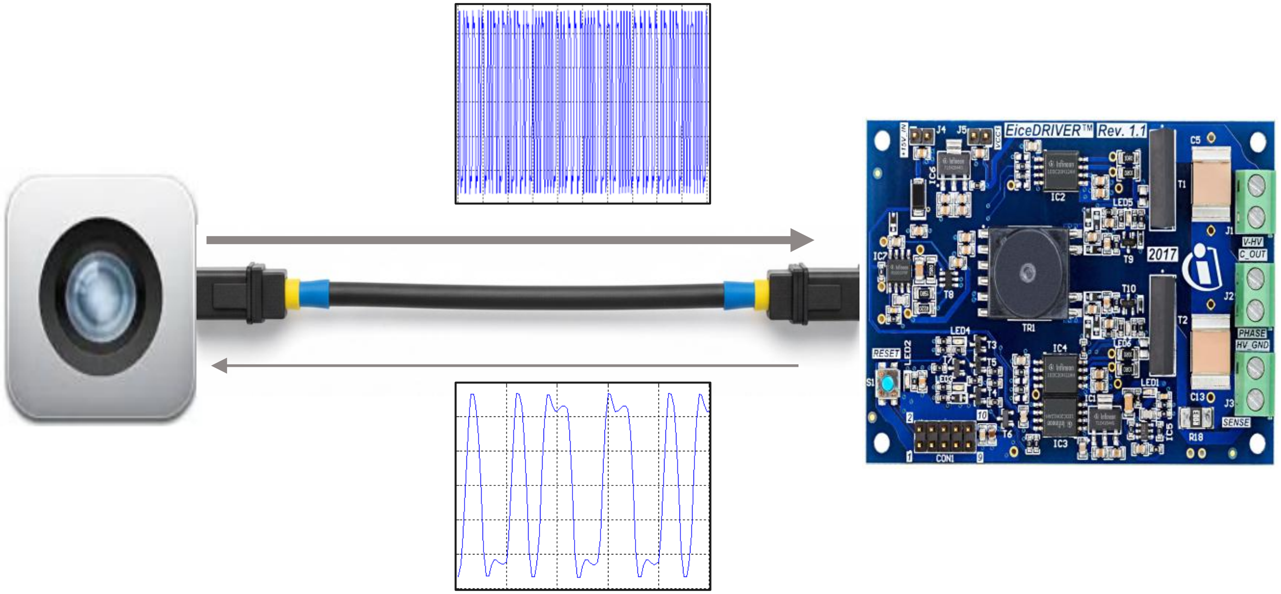
Test Mode Definition for the Crystal-less Camera Operation

Alireza Razavi, Sam Johnson, Fan Wei

Extra requirement on low data rate signal in crystal-less operation

- Crystal-less mode introduces an additional requirement on the low data rate signal
- Low data rate signal provides the clock for high data rate transmitter
- The transition time should be sharp enough for timing recovery
- This requirement is similar in existing requirement in other IEEE SerDes standard such as 10GBASE-KR



Transition time test using ACT method

- The rise/fall transition time between 20% and 80% levels of the steady state voltage amplitude shall be less than TBD ns.
- Measurement shall be performed using an all-ones sequence applied to the DME mapper. This sequence generates a deterministic square wave with frequency of 117MHz